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Electronic Patent Application Submission

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EFS ID:	54621
Application ID:	10679617
Title of Invention:	METHODS AND SYSTEMS FOR RETICLE INSPECTION AND DEFECT REVIEW USING AERIAL IMAGING
First Named Inventor:	Stan Stokowski
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Electronic Version v1.1
Stylesheet Version v1.1.0

Title of Invention	METHODS AND SYSTEMS FOR RETICLE INSPECTION AND DEFECT REVIEW USING AERIAL IMAGING

Application Number: 10/679617
Date: 2003-10-06
First Named Applicant: Stan Stokowski

Confirmation Number: 3334
Attorney Docket Number: 5589-04101

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Submitted by:	Elec. Sign.	Sign. Capacity
Kevin L. Daffer Registered Number: 34146	Kevin L. Daffer	Attorney

Documents being submitted	Files
us-ids	558904001IDS-usidst.xml us-ids.dtd us-ids.xsl

Comments

ELECTRONIC INFORMATION DISCLOSURE STATEMENT

Electronic Version v18
Stylesheet Version v18.0

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Confirmation Number: 3334
First Named Applicant: Stan Stokowski
Attorney Docket Number: 5589-04101
Search string: (5980187 or 5619548 or 6104835 or 6233719 or 5991699 or 5689614 or 4247203 or 4347001 or 4378159 or 4448532 or 4532650 or 4555798 or 4579455 or 4633504 or 4641967 or 4758094 or 4766324 or 4805123 or 4845558 or 4877326 or 4926489 or 5189481 or 5563702 or 5572598 or 5737072 or 5889593 or 6052478 or 6076465 or 6122046 or 6137570 or 6141038 or 6175645 or 6282309 or 6363166).pn.

US Patent Documents

Note: Applicant is not required to submit a paper copy of cited US Patent Documents

init	Cite.No.	Patent No.	Date	Patentee	Kind	Class	Subclass
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	2	5619548	1997-04-08	Koppel			
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Signature

Examiner Name	Date